

JEOL 7600F: Analytical High Resolution SEM

Main imaging capabilities

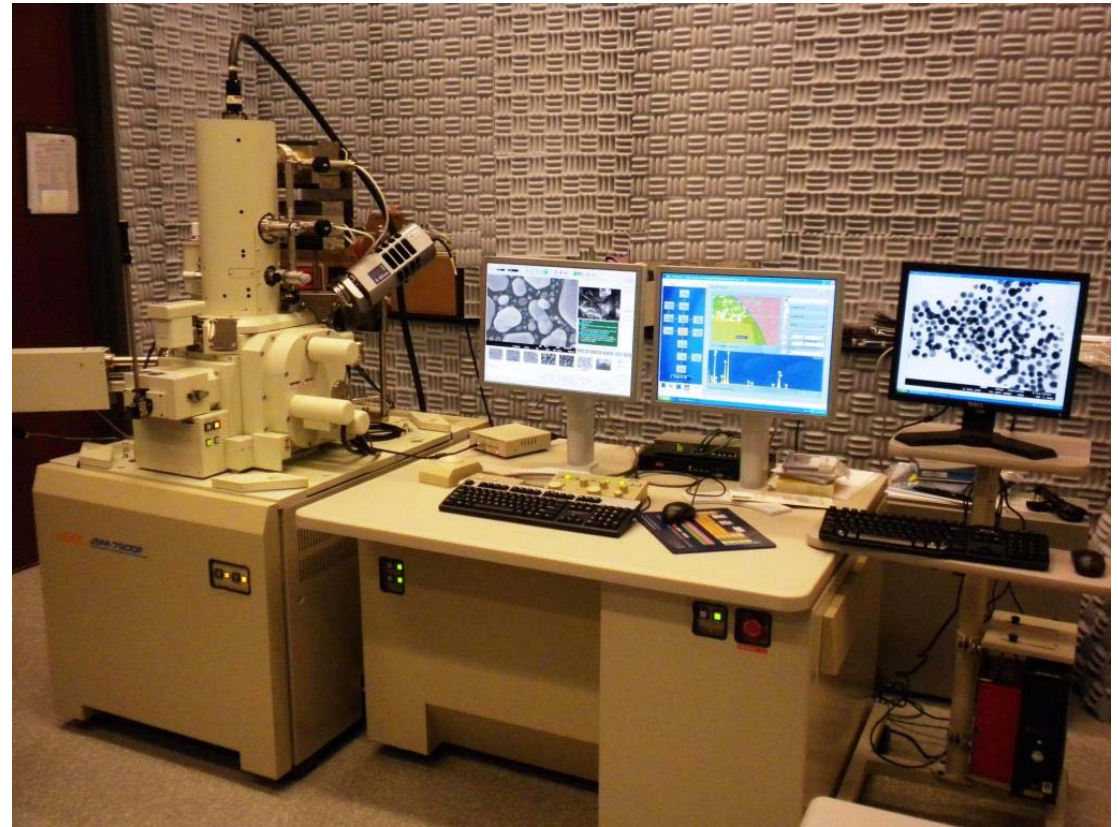
- High resolution: 1.0 nm at 15 keV
1.5 nm at 1 kV
5.0 nm at 0.1 kV
- STEM imaging: 0.8 nm at 30 kV
- Probe current: 0.1 pA to 200 nA
- Low Angle Backscattered Electron Detector (LABe):
 - Hi-res backscattered electron (BSE) imaging at low energies.

X-ray analysis capabilities

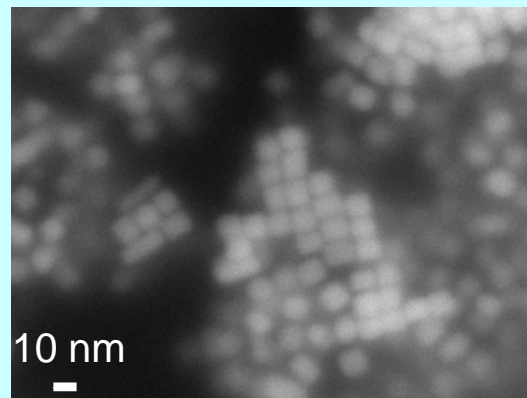
- Energy dispersive spectrometer:
80 mm² silicon drift detector
(129 eV resolution)
- Wavelength dispersive spectrometer:
Five diffracting crystals to analyze
down to Be (Z=4)

Miscellaneous

- Alicona MeX software package for surface metrology using SEM stereoscopic images

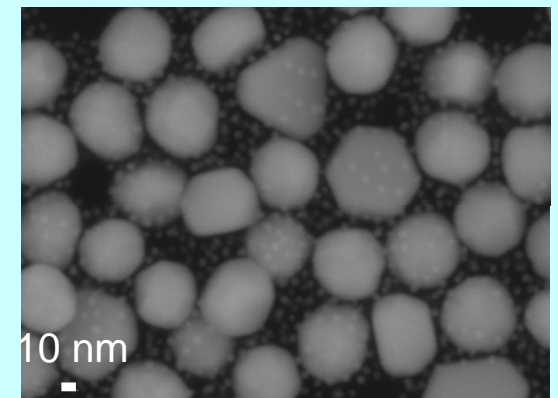


Dodecanethiol ligated palladium nanocubes
(sample uncoated)



Sample courtesy of Y. Zhang (CFN)

Binary mixture of Au nanoparticles
interconnected with DNA
(sample uncoated)



Sample courtesy of D. Nykypanchuk (CFN)